

Physical Properties		Chemical Properties		Mechanical Properties		Thermal Properties		Electrical Properties		Optical Properties		Acoustic Properties		Magnetic Properties		Biological Properties		Environmental Properties	
Parameter	Value	Parameter	Value	Parameter	Value	Parameter	Value	Parameter	Value	Parameter	Value	Parameter	Value	Parameter	Value	Parameter	Value	Parameter	Value
Length	1.2 m	Weight	0.5 kg	Strength	100 N	Temperature	25 °C	Resistance	10 Ω	Transmittance	90%	Speed of Sound	340 m/s	Permeability	1.25	Toxicity	Low	Biodegradability	High
Width	0.1 m	Volume	0.05 m³	Stiffness	1000 N/m	Humidity	50%	Capacitance	100 pF	Absorbance	0.1	Frequency	1000 Hz	Conductivity	0.01 S/m	Flammability	Low	Corrosion Resistance	High
Height	0.05 m	Surface Area	0.1 m²	Modulus	100 GPa	Pressure	1 atm	Inductance	100 nH	Reflectance	10%	Wavelength	1000 nm	Dielectric Constant	1.5	Reactivity	Low	Stability	High
Mass	0.5 kg	Density	1000 kg/m³	Hardness	1000 MPa	Current	1 A	Frequency	100 kHz	Phase Shift	0°	Intensity	100 W/m²	Loss Tangent	0.01	Biocompatibility	High	Recyclability	High
Volume	0.05 m³	Specific Gravity	1.0	Toughness	100 J/m²	Voltage	1 V	Wavelength	1000 nm	Modulation Index	0.5	Coherence Length	100 μm	Quality Factor	100	Genotoxicity	Low	Environmental Impact	Low
Surface Area	0.1 m²	Porosity	10%	Impact Resistance	100 J	Power	1 W	Bandwidth	100 MHz	Extinction Coefficient	0.1	Optical Loss	10%	Thermal Conductivity	1 W/mK	Mutagenicity	Low	Carbon Footprint	Low
Density	1000 kg/m³	Thermal Conductivity	1 W/mK	Fatigue Life	10000 cycles	Efficiency	10%	Signal-to-Noise Ratio	10 dB	Group Delay	10 ns	Dispersion	10 ps/nm	Thermal Expansion Coefficient	10 ppm/K	Carcinogenicity	Low	Water Footprint	Low
Specific Gravity	1.0	Thermal Expansion Coefficient	10 ppm/K	Creep Resistance	High	Reliability	High	Dynamic Range	100 dB	Nonlinearity	Low	Scattering Coefficient	0.1	Thermal Shock Resistance	High	Reproductive Toxicity	Low	Energy Footprint	Low
Porosity	10%	Thermal Shock Resistance	High	Stress Relaxation	Low	Accuracy	High	Linearity	High	Harmonic Distortion	Low	Diffraction Efficiency	10%	Thermal Stability	High	Developmental Toxicity	Low	Material Footprint	Low
Thermal Conductivity	1 W/mK	Stress Relaxation	Low	Strain Rate Sensitivity	Low	Precision	High	Stability	High	Intermodulation	Low	Conversion Efficiency	10%	Thermal Hysteresis	Low	Immunotoxicity	Low	Land Use Footprint	Low
Thermal Expansion Coefficient	10 ppm/K	Strain Rate Sensitivity	Low	Temperature Sensitivity	Low	Resolution	High	Repeatability	High	Spurious Emissions	Low	Quantum Efficiency	10%	Thermal Aging	High	Subchronic Toxicity	Low	Water Pollution Footprint	Low
Thermal Shock Resistance	High	Temperature Sensitivity	Low	Humidity Sensitivity	Low	Throughput	High	Consistency	High	Phase Noise	Low	Excitation Wavelength	1000 nm	Thermal Cycling	High	Chronic Toxicity	Low	Air Pollution Footprint	Low
Stress Relaxation	Low	Humidity Sensitivity	Low	Pressure Sensitivity	Low	Yield	High	Uniformity	High	Amplitude Modulation	Low	Emission Wavelength	1000 nm	Thermal Annealing	High	Acute Toxicity	Low	Soil Pollution Footprint	Low
Strain Rate Sensitivity	Low	Pressure Sensitivity	Low	Current Sensitivity	Low	Defect Density	Low	Adhesion	High	Frequency Modulation	Low	Excitation Intensity	100 W/m²	Thermal Etching	High	Genotoxicity	Low	Water Pollution Footprint	Low
Temperature Sensitivity	Low	Current Sensitivity	Low	Voltage Sensitivity	Low	Crack Density	Low	Cohesion	High	Phase Locking	Low	Emission Intensity	100 W/m²	Thermal Deposition	High	Carcinogenicity	Low	Air Pollution Footprint	Low
Humidity Sensitivity	Low	Voltage Sensitivity	Low	Power Sensitivity	Low	Dislocation Density	Low	Surface Energy	High	Phase Shifting	Low	Emission Wavelength	1000 nm	Thermal Evaporation	High	Reproductive Toxicity	Low	Water Pollution Footprint	Low
Pressure Sensitivity	Low	Power Sensitivity	Low	Efficiency Sensitivity	Low	Grain Size	100 nm	Wettability	High	Phase Modulation	Low	Emission Wavelength	1000 nm	Thermal Sputtering	High	Developmental Toxicity	Low	Air Pollution Footprint	Low
Current Sensitivity	Low	Efficiency Sensitivity	Low	Reliability Sensitivity	Low	Surface Roughness	10 nm	Adhesion Energy	10 J/m²	Phase Shifting	Low	Emission Wavelength	1000 nm	Thermal Oxidation	High	Chronic Toxicity	Low	Soil Pollution Footprint	Low
Voltage Sensitivity	Low	Reliability Sensitivity	Low	Accuracy Sensitivity	Low	Volume Fraction	10%	Interfacial Energy	10 J/m²	Phase Shifting	Low	Emission Wavelength	1000 nm	Thermal Annealing	High	Subchronic Toxicity	Low	Air Pollution Footprint	Low
Power Sensitivity	Low	Accuracy Sensitivity	Low	Precision Sensitivity	Low	Porosity	10%	Thermal Conductivity	1 W/mK	Phase Shifting	Low	Emission Wavelength	1000 nm	Thermal Curing	High	Acute Toxicity	Low	Water Pollution Footprint	Low
Efficiency Sensitivity	Low	Precision Sensitivity	Low	Resolution Sensitivity	Low	Crack Density	Low	Thermal Expansion Coefficient	10 ppm/K	Phase Shifting	Low	Emission Wavelength	1000 nm	Thermal Drying	High	Genotoxicity	Low	Air Pollution Footprint	Low
Reliability Sensitivity	Low	Resolution Sensitivity	Low	Throughput Sensitivity															

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Examination of claims 64-67 is requested.

Dated: 08 May 2001

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No. .... 09/561,794  
Priority Filing Date ..... May 1, 2000  
Inventor ..... Alan R. Reinberg  
Assignee ..... Micron Technology, Inc.  
Priority Group Art Unit ..... 2811  
Priority Examiner ..... C. Nguyen  
Attorney's Docket No. .... MI22-1704  
Title: Microelectronic Device Fabricating Method, Integrated Circuit, and  
Intermediate Construction

Assistant Commissioner for Patents  
Washington, D. C. 20231  
Attention: Official Draftsman

**LETTER SUBMITTING FORMAL DRAWINGS**


Please enter the enclosed formal drawings in the above-referenced application in place of the originally filed drawings.

Acknowledgment of receipt of the formal drawing sheets and their acceptance into the file is requested.

Respectfully submitted,

Date: 08 May 2001

By:

  
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Enclosures: Nine (9) sheets of drawings (Fig. 1A-20B)

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